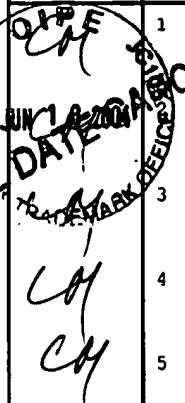
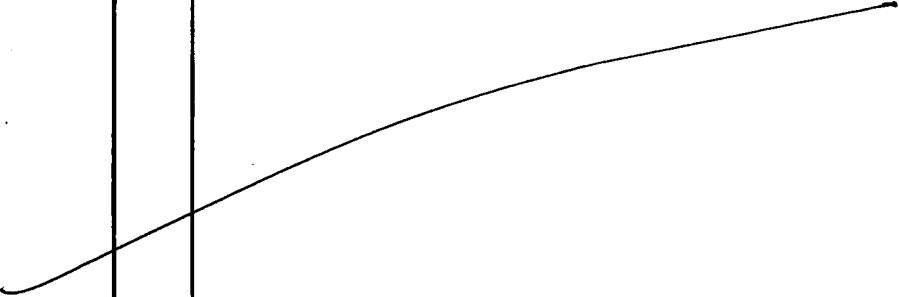
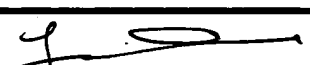


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Substitute for Form 1449A/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>				Application Number		10/650,059	
				Filing Date		August 27, 2003	
				First Named Inventor		Ryouichi YOKOYAMA et al	
				Group Art Unit		2855	
				Examiner Name			
Sheet	1	of	1	Attorney Docket Number		03506/LH	
<b>OTHER DOCUMENTS - NON-PATENT LITERATURE DOCUMENTS</b>							
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Include name of author (in CAPITAL LETTERS), title of article, title of item, date, page(s), volume-issue number(s), publisher, city and/or country where published					T <sup>2</sup>
 MAIL DATE CANCELLED CH CH	1	K. TANAKA, K. ISHIHARA and K. INOUE: "A METHOD OF X-RAY STRESS MANAGEMENT FOR CUBIC POLYCRYSTALS WITH FIBER TEXTURE", J. Soc. Mat. Sci., Japan, Vol. 45, No. 8, pages 945-950, August, 1996.					
	3	K. TANAKA, Y. AKINIWA, T. ITO and K. INOUE: "ELASTIC CONSTANTS AND X-RAY STRESS MEASUREMENT OF CUBIC THIN FILMS WITH FIBER TEXTURE", JSME International Journal, Series A, Vol. 42, No. 2, pages 224-234, 1998.					
	4	Jikkenbutsurigaku kouza 20, X-sen kaisetsu (Experimental physics course 20, x-ray diffraction), edited by K. Kohra, KYORITSU SHUPPAN CO., LTD., 1998, pages 571-575, "16.2 x-sen ouryokusokuteino genri (Principle of X-ray stress measurement)".					
	5	X-sen kesshoukaisekino tebiki, Ouyoubutsurigaku sensho (Guide to X-ray Crystal Analysis, Applied Physics Sampler), T. Sakurai, Shokabou, 1983, page 53.					
							
Examiner Signature				Date Considered		11/22/04	

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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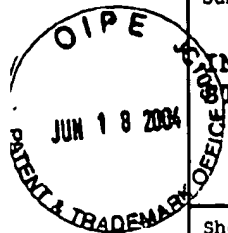
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				Group Art Unit	2855
				Examiner Name	
Sheet	1	of	2	Attorney Docket Number	03506/LH

**OTHER DOCUMENTS - NON-PATENT LITERATURE DOCUMENTS**

Examiner Initials	Citation No. <sup>1</sup>	Include name of author (in CAPITAL LETTERS), title of article, title of item, date, page(s), volume-issue number(s), publisher, city and/or country where published	T <sup>2</sup>
CM	2	Tanaka et al., "X-ray residual stress measurement of aluminum thin films with 111 fiber texture" Journal of the Society of Materials Science, Japan, Soc. Mater. Sci. Japan, Japan, Vol. 45, No. 10, pages 1138-1144, XP00902646, ISSN: 0514-5163, October 1996.	
CM	3	Lappalainen J. Et al., "Electrical and Mechanical Properties of Ferroelectric Thin Films Laser Ablated from a PBO.97NDO.02 (ZRO.55TI0.45)03 Target" Journal of Applied Physics, American Institute of Physics. New York, US, Vol. 82, No. 7, pages 3469-3477, XP000738070, ISSN: 0021-8979, October 1, 1997.	
Examiner Signature			Date Considered
		11/22/04	

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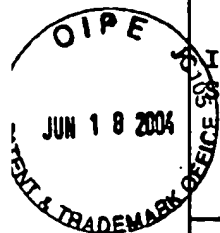
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Sheet	1	of	2	Attorney Docket Number	03506/LH

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Exam. Inits*	Cite No <sup>1</sup>	Document Number	Kind Code <sup>2</sup>	Name of Patentee or Applicant	Publication Date MM-DD-YYYY	Relevant Portion

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Exam. Inits*	Cite No <sup>1</sup>	Offc	Document Number <sup>4</sup>	Kind Code <sup>5</sup>	Name of Patentee or Applicant	Publication Date MM-DD-YYYY	Relevant Portion	T <sup>6</sup>
CM	1	DE	197 19 473	A1	FRAUNHOFER GES FORSCHUNG	04-02-1998		

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